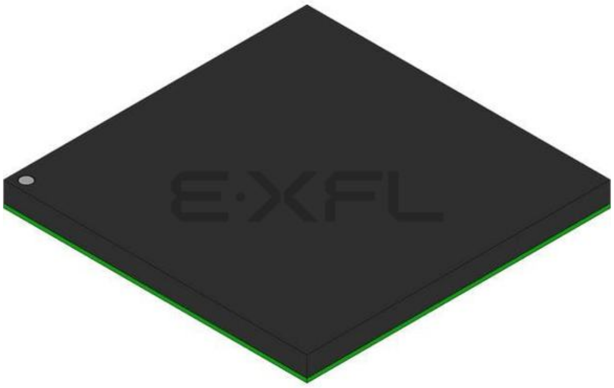
Freescale Semiconductor - MPC8321VRADDC Datasheet



Welcome to E-XFL.COM

Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC e300c2
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	266MHz
Co-Processors/DSP	Communications; QUICC Engine
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100Mbps (3)
SATA	-
USB	USB 2.0 (1)
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	516-BBGA
Supplier Device Package	516-PBGA (27x27)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=mpc8321vraddc

1.1.2 Serial Interfaces

The MPC8323E serial interfaces are as follows:

- Support for one UL2 interface with 31 multi-PHY addresses (MPC8323E and MPC8323 only)
- Support for up to three 10/100 Mbps Ethernet interfaces using MII or RMII
- Support for up to four T1/E1/J1/E3 or DS-3 serial interfaces (TDM)
- Support for dual UART and SPI interfaces and a single I^{2}C interface

1.2 QUICC Engine Block

The QUICC Engine block is a versatile communications complex that integrates several communications peripheral controllers. It provides on-chip system design for a variety of applications, particularly in communications and networking systems. The QUICC Engine block has the following features:

- One 32-bit RISC controller for flexible support of the communications peripherals
- Serial DMA channel for receive and transmit on all serial channels
- Five universal communication controllers (UCCs) supporting the following protocols and interfaces (not all of them simultaneously):
    - 10/100 Mbps Ethernet/IEEE 802.3® standard
    - IP support for IPv4 and IPv6 packets including TOS, TTL, and header checksum processing
    - ATM protocol through UTOPIA interface (note that the MPC8321 and MPC8321E do not support the UTOPIA interface)
    - HDLC /transparent up to 70-Mbps full-duplex
    - HDLC bus up to 10 Mbps
    - Asynchronous HDLC
    - UART
    - BISYNC up to 2 Mbps
    - QUICC multi-channel controller (QMC) for 64 TDM channels
- One UTOPIA interface (UPC1) supporting 31 multi-PHYs (MPC8323E- and MPC8323-specific)
- Two serial peripheral interfaces (SPI). SPI2 is dedicated to Ethernet PHY management.
- Four TDM interfaces
- Thirteen independent baud rate generators and 19 input clock pins for supplying clocks to UCC serial channels
- Four independent 16-bit timers that can be interconnected as two 32-bit timers

The UCCs are similar to the PowerQUICC II peripherals: SCC (BISYNC, UART, and HDLC bus) and FCC (fast Ethernet, HDLC, transparent, and ATM).

6.2 DDR1 and DDR2 SDRAM AC Electrical Characteristics

This section provides the AC electrical characteristics for the DDR1 and DDR2 SDRAM interface.

6.2.1 DDR1 and DDR2 SDRAM Input AC Timing Specifications

Table 16 provides the input AC timing specifications for the DDR2 SDRAM (D*n*_GV_{DD}(typ) = 1.8 V).

Table 16. DDR2 SDRAM Input AC Timing Specifications for 1.8-V Interface

At recommended operating conditions with D*n*_GV_{DD} of 1.8 ± 5%.

Parameter	Symbol	Min	Max	Unit	Notes
AC input low voltage	V_{IL}	—	MVREFn_{REF} – 0.25	V	—
AC input high voltage	V_{IH}	MVREFn_{REF} + 0.25	—	V	—

Table 17 provides the input AC timing specifications for the DDR1 SDRAM (D*n*_GV_{DD}(typ) = 2.5 V).

Table 17. DDR1 SDRAM Input AC Timing Specifications for 2.5 V Interface

At recommended operating conditions with D*n*_GV_{DD} of 2.5 ± 5%.

Parameter	Symbol	Min	Max	Unit	Notes
AC input low voltage	V_{IL}	—	MVREFn_{REF} – 0.31	V	—
AC input high voltage	V_{IH}	MVREFn_{REF} + 0.31	—	V	—

Table 18 provides the input AC timing specifications for the DDR1 and DDR2 SDRAM interface.

Table 18. DDR1 and DDR2 SDRAM Input AC Timing Specifications

At recommended operating conditions with D*n*_GV_{DD} of (1.8 or 2.5 V) ± 5%.

Parameter	Symbol	Min	Max	Unit	Notes
Controller skew for MDQS—MDQ/MDM	t_{CISKEW}			ps	1, 2
266 MHz		–750	750		
200 MHz		–1250	1250		

Notes:

1. t_{CISKEW} represents the total amount of skew consumed by the controller between MDQS[n] and any corresponding bit that is captured with MDQS[n]. This should be subtracted from the total timing budget.
2. The amount of skew that can be tolerated from MDQS to a corresponding MDQ signal is called t_{DISKEW}. This can be determined by the following equation: $t_{DISKEW} = \pm(T/4 - \mathrm{abs}(t_{CISKEW}))$ where T is the clock period and abs(t_{CISKEW}) is the absolute value of t_{CISKEW}.

8.2.2.1 RMII Transmit AC Timing Specifications

Table 23 provides the RMII transmit AC timing specifications.

Table 25. RMII Transmit AC Timing Specifications

At recommended operating conditions with OV_{DD} of 3.3 V ± 10%.

Parameter/Condition	Symbol[1]	Min	Typical	Max	Unit
REF_CLK clock	t_{RMX}	—	20	—	ns
REF_CLK duty cycle	t_{RMXH}/t_{RMX}	35	—	65	%
REF_CLK to RMII data TXD[1:0], TX_EN delay	$t_{RMTKHDX}$	2	—	10	ns
REF_CLK data clock rise V_{IL}(min) to V_{IH}(max)	t_{RMXR}	1.0	—	4.0	ns
REF_CLK data clock fall V_{IH}(max) to V_{IL}(min)	t_{RMXF}	1.0	—	4.0	ns

Note:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first three letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{RMTKHDX}$ symbolizes RMII transmit timing (RMT) for the time t_{RMX} clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of t_{RMX} represents the RMII(RM) reference (X) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

Figure 10 shows the RMII transmit AC timing diagram.

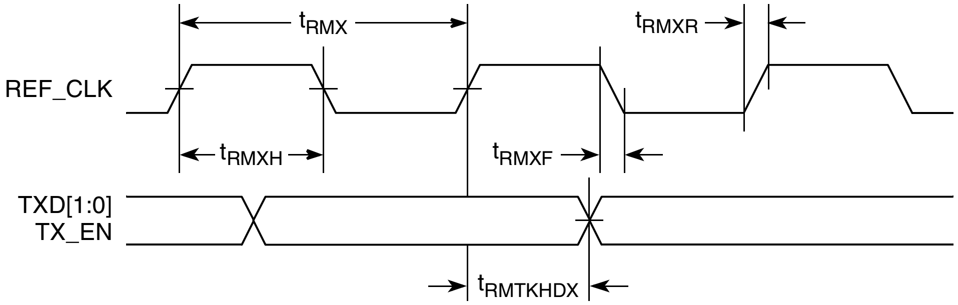


Figure 10. RMII Transmit AC Timing Diagram

8.2.2.2 RMII Receive AC Timing Specifications

Table 24 provides the RMII receive AC timing specifications.

Table 26. RMII Receive AC Timing Specifications

At recommended operating conditions with OV_{DD} of 3.3 V ± 10%.

Parameter/Condition	Symbol[1]	Min	Typical	Max	Unit
REF_CLK clock period	t_{RMX}	—	20	—	ns
REF_CLK duty cycle	t_{RMXH}/t_{RMX}	35	—	65	%
RXD[1:0], CRS_DV, RX_ER setup time to REF_CLK	$t_{RMRDVKH}$	4.0	—	—	ns
RXD[1:0], CRS_DV, RX_ER hold time to REF_CLK	$t_{RMRDXKH}$	2.0	—	—	ns
REF_CLK clock rise V_{IL}(min) to V_{IH}(max)	t_{RMXR}	1.0	—	4.0	ns

Table 26. RMII Receive AC Timing Specifications (continued)

At recommended operating conditions with OV_{DD} of 3.3 V ± 10%.

Parameter/Condition	Symbol[1]	Min	Typical	Max	Unit
REF_CLK clock fall time V_{IH}(max) to V_{IL}(min)	t_{RMXF}	1.0	—	4.0	ns

Note:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first three letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{RMRDVKH}$ symbolizes RMII receive timing (RMR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{RMX} clock reference (K) going to the high (H) state or setup time. Also, $t_{RMRDXKL}$ symbolizes RMII receive timing (RMR) with respect to the time data input signals (D) went invalid (X) relative to the t_{RMX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{RMX} represents the RMII (RM) reference (X) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

Figure 11 provides the AC test load.

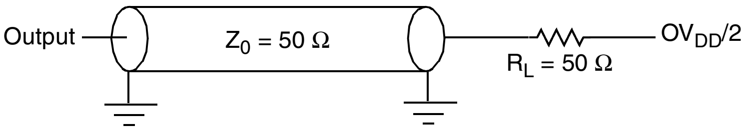


Figure 11. AC Test Load

Figure 12 shows the RMII receive AC timing diagram.

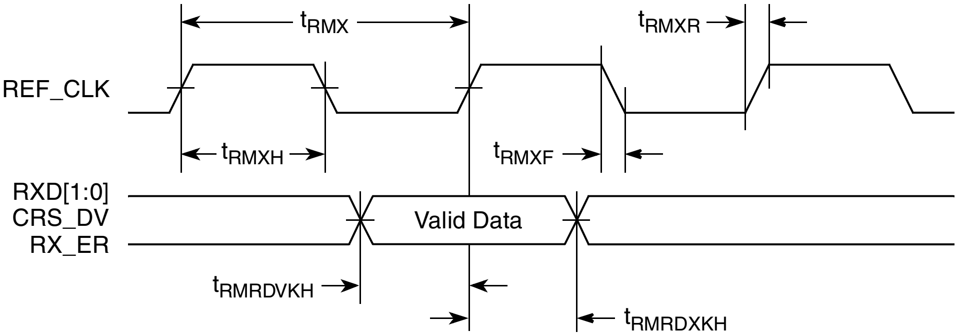


Figure 12. RMII Receive AC Timing Diagram

8.3 Ethernet Management Interface Electrical Characteristics

The electrical characteristics specified here apply to MII management interface signals MDIO (management data input/output) and MDC (management data clock). The electrical characteristics for MII, and RMII are specified in Section 8.1, “Ethernet Controller (10/100 Mbps)—MII/RMII Electrical Characteristics.”

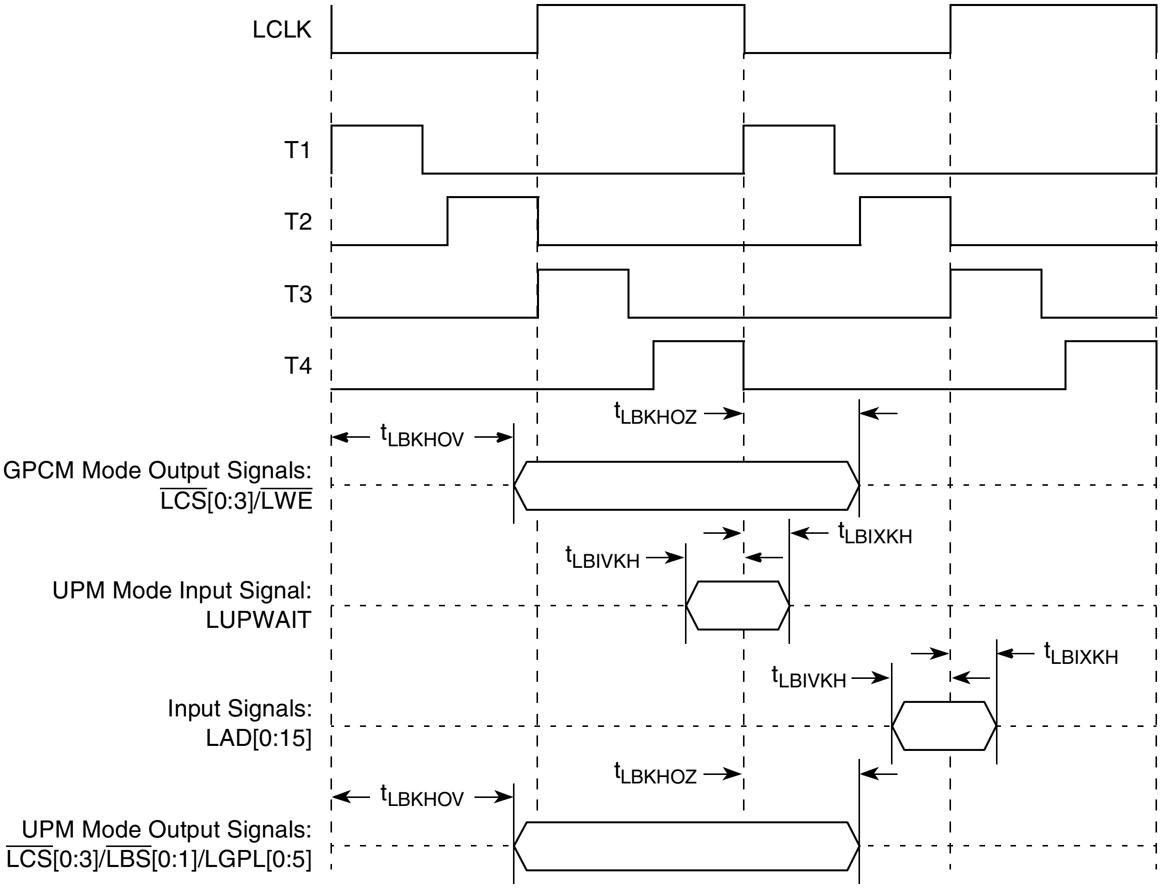


Figure 17. Local Bus Signals, GPCM/UPM Signals for LCRR[CLKDIV] = 4

10 JTAG

This section describes the DC and AC electrical specifications for the IEEE Std. 1149.1™ (JTAG) interface of the MPC8323E.

10.1 JTAG DC Electrical Characteristics

Table 31 provides the DC electrical characteristics for the IEEE Std. 1149.1 (JTAG) interface of the MPC8323E.

Table 31. JTAG Interface DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit
Output high voltage	V_{OH}	$I_{OH} = -6.0$ mA	2.4	—	V
Output low voltage	V_{OL}	$I_{OL} = 6.0$ mA	—	0.5	V
Output low voltage	V_{OL}	$I_{OL} = 3.2$ mA	—	0.4	V
Input high voltage	V_{IH}	—	2.5	$OV_{DD} + 0.3$	V

Table 31. JTAG Interface DC Electrical Characteristics (continued)

Characteristic	Symbol	Condition	Min	Max	Unit
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	$0\ V \le V_{IN} \le OV_{DD}$	—	±5	μA

10.2 JTAG AC Electrical Characteristics

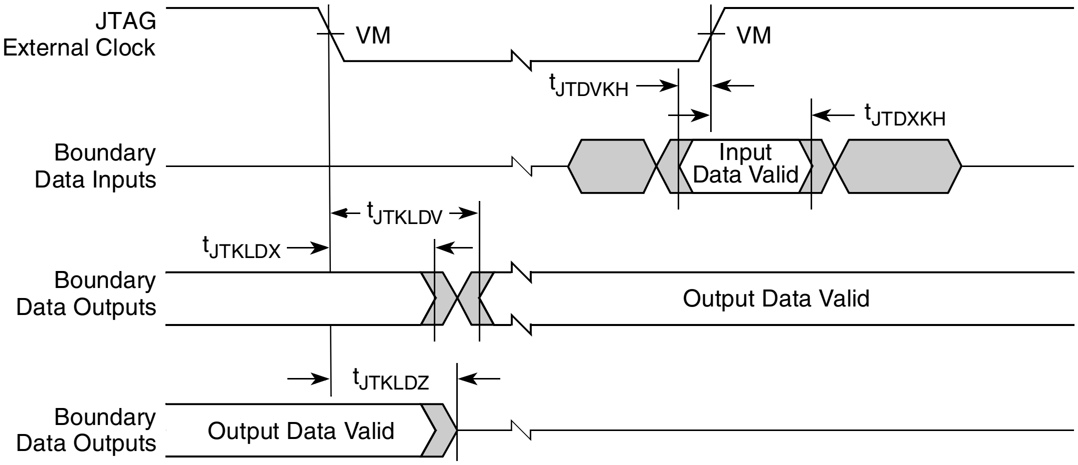
This section describes the AC electrical specifications for the IEEE Std. 1149.1 (JTAG) interface of the MPC8323E. Table 32 provides the JTAG AC timing specifications as defined in Figure 19 through Figure 22.

Table 32. JTAG AC Timing Specifications (Independent of CLKIN)[1]

At recommended operating conditions (see Table 2).

Parameter	Symbol[2]	Min	Max	Unit	Notes
JTAG external clock frequency of operation	f_{JTG}	0	33.3	MHz	—
JTAG external clock cycle time	t_{JTG}	30	—	ns	—
JTAG external clock pulse width measured at 1.4 V	t_{JTKHKL}	11	—	ns	—
JTAG external clock rise and fall times	t_{JTGR}, t_{JTGF}	0	2	ns	—
$\overline{\text{TRST}}$ assert time	t_{TRST}	25	—	ns	3
Input setup times:				ns	4
Boundary-scan data	t_{JTDVKH}	4	—		
TMS, TDI	t_{JTIVKH}	4	—		
Input hold times:				ns	4
Boundary-scan data	t_{JTDXKH}	10	—		
TMS, TDI	t_{JTIXKH}	10	—		
Valid times:				ns	5
Boundary-scan data	t_{JTKLDV}	2	15		
TDO	t_{JTKLOV}	2	15		
Output hold times:				ns	5
Boundary-scan data	t_{JTKLDX}	2	—		
TDO	t_{JTKLOX}	2	—		

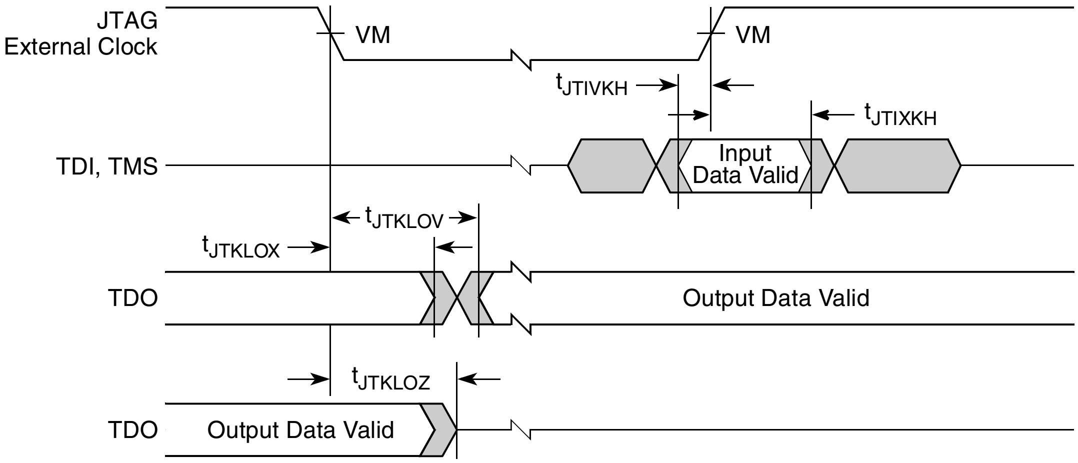
Figure 21 provides the boundary-scan timing diagram.



VM = Midpoint Voltage (OV_{DD}/2)

Figure 21. Boundary-Scan Timing Diagram

Figure 22 provides the test access port timing diagram.



VM = Midpoint Voltage (OV_{DD}/2)

Figure 22. Test Access Port Timing Diagram

Table 37 shows the PCI AC timing specifications at 33 MHz.

Table 37. PCI AC Timing Specifications at 33 MHz

Parameter	Symbol[1]	Min	Max	Unit	Notes
Clock to output valid	t_{PCKHOV}	—	11	ns	2
Output hold from clock	t_{PCKHOX}	2	—	ns	2
Clock to output high impedence	t_{PCKHOZ}	—	14	ns	2, 3
Input setup to clock	t_{PCIVKH}	3.0	—	ns	2, 4
Input hold from clock	t_{PCIXKH}	0	—	ns	2, 4

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{PCIVKH} symbolizes PCI timing (PC) with respect to the time the input signals (I) reach the valid state (V) relative to the PCI_SYNC_IN clock, t_{SYS}, reference (K) going to the high (H) state or setup time. Also, t_{PCRHFV} symbolizes PCI timing (PC) with respect to the time hard reset (R) went high (H) relative to the frame signal (F) going to the valid (V) state.
2. See the timing measurement conditions in the *PCI 2.3 Local Bus Specifications*.
3. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
4. Input timings are measured at the pin.

Figure 25 provides the AC test load for PCI.

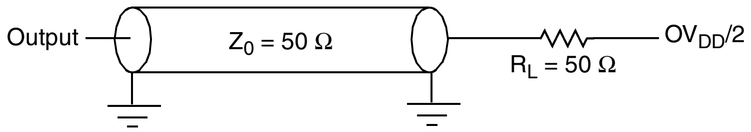


Figure 25. PCI AC Test Load

Figure 26 shows the PCI input AC timing conditions.

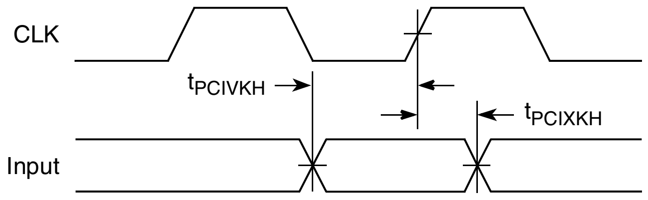


Figure 26. PCI Input AC Timing Measurement Conditions

Figure 27 shows the PCI output AC timing conditions.

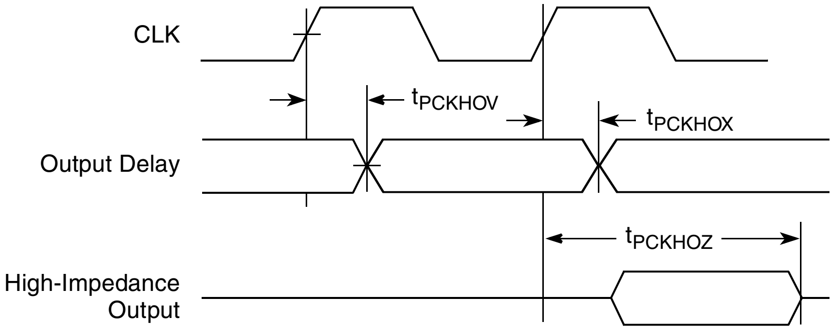


Figure 27. PCI Output AC Timing Measurement Condition

13 Timers

This section describes the DC and AC electrical specifications for the timers of the MPC8323E.

13.1 Timer DC Electrical Characteristics

Table 38 provides the DC electrical characteristics for the MPC8323E timer pins, including TIN, $\overline{\text{TOUT}}$, $\overline{\text{TGATE}}$, and RTC_CLK.

Table 38. Timer DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit
Output high voltage	V_{OH}	$I_{OH} = -6.0$ mA	2.4	—	V
Output low voltage	V_{OL}	$I_{OL} = 6.0$ mA	—	0.5	V
Output low voltage	V_{OL}	$I_{OL} = 3.2$ mA	—	0.4	V
Input high voltage	V_{IH}	—	2.0	$OV_{DD} + 0.3$	V
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	$0 \text{ V} \le V_{IN} \le OV_{DD}$	—	±5	μA

13.2 Timer AC Timing Specifications

Table 39 provides the timer input and output AC timing specifications.

Table 39. Timer Input AC Timing Specifications[1]

Characteristic	Symbol[2]	Min	Unit
Timers inputs—minimum pulse width	t_{TIWID}	20	ns

Notes:

1. Input specifications are measured from the 50% level of the signal to the 50% level of the rising edge of CLKIN. Timings are measured at the pin.
2. Timer inputs and outputs are asynchronous to any visible clock. Timer outputs should be synchronized before use by any external synchronous logic. Timer inputs are required to be valid for at least t_{TIWID} ns to ensure proper operation.

16 SPI

This section describes the DC and AC electrical specifications for the SPI of the MPC8323E.

16.1 SPI DC Electrical Characteristics

Table 44 provides the DC electrical characteristics for the MPC8323E SPI.

Table 44. SPI DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit
Output high voltage	V_{OH}	I_{OH} = –6.0 mA	2.4	—	V
Output low voltage	V_{OL}	I_{OL} = 6.0 mA	—	0.5	V
Output low voltage	V_{OL}	I_{OL} = 3.2 mA	—	0.4	V
Input high voltage	V_{IH}	—	2.0	OV_{DD} + 0.3	V
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	$0 \text{ V} \le V_{IN} \le OV_{DD}$	—	±5	μA

16.2 SPI AC Timing Specifications

Table 45 and provide the SPI input and output AC timing specifications.

Table 45. SPI AC Timing Specifications[1]

Characteristic	Symbol[2]	Min	Max	Unit
SPI outputs—Master mode (internal clock) delay	t_{NIKHOV}	0.5	6	ns
SPI outputs—Slave mode (external clock) delay	t_{NEKHOV}	2	8	ns
SPI inputs—Master mode (internal clock) input setup time	t_{NIIVKH}	6	—	ns
SPI inputs—Master mode (internal clock) input hold time	t_{NIIXKH}	0	—	ns
SPI inputs—Slave mode (external clock) input setup time	t_{NEIVKH}	4	—	ns
SPI inputs—Slave mode (external clock) input hold time	t_{NEIXKH}	2	—	ns

Notes:

1. Output specifications are measured from the 50% level of the rising edge of CLKIN to the 50% level of the signal. Timings are measured at the pin.
2. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{NIKHOV} symbolizes the NMSI outputs internal timing (NI) for the time t_{SPI} memory clock reference (K) goes from the high state (H) until outputs (O) are valid (V).

Figure 30 provides the AC test load for the SPI.

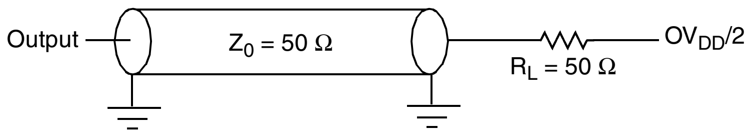


Figure 30. SPI AC Test Load

Table 46. TDM/SI DC Electrical Characteristics (continued)

Characteristic	Symbol	Condition	Min	Max	Unit
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	$0\ V \le V_{IN} \le OV_{DD}$	—	±5	μA

17.2 TDM/SI AC Timing Specifications

Table 47 provides the TDM/SI input and output AC timing specifications.

Table 47. TDM/SI AC Timing Specifications[1]

Characteristic	Symbol[2]	Min	Max	Unit
TDM/SI outputs—External clock delay	t_{SEKHOV}	2	12	ns
TDM/SI outputs—External clock High Impedance	t_{SEKHOX}	2	10	ns
TDM/SI inputs—External clock input setup time	t_{SEIVKH}	5	—	ns
TDM/SI inputs—External clock input hold time	t_{SEIXKH}	2	—	ns

Notes:

1. Output specifications are measured from the 50% level of the rising edge of CLKIN to the 50% level of the signal. Timings are measured at the pin.
2. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{SEKHOX} symbolizes the TDM/SI outputs external timing (SE) for the time $t_{TDM/SI}$ memory clock reference (K) goes from the high state (H) until outputs (O) are invalid (X).

Figure 33 provides the AC test load for the TDM/SI.

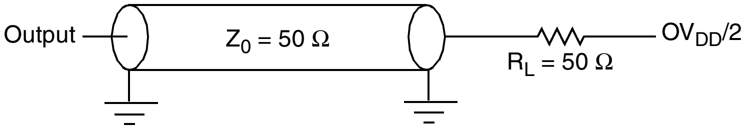
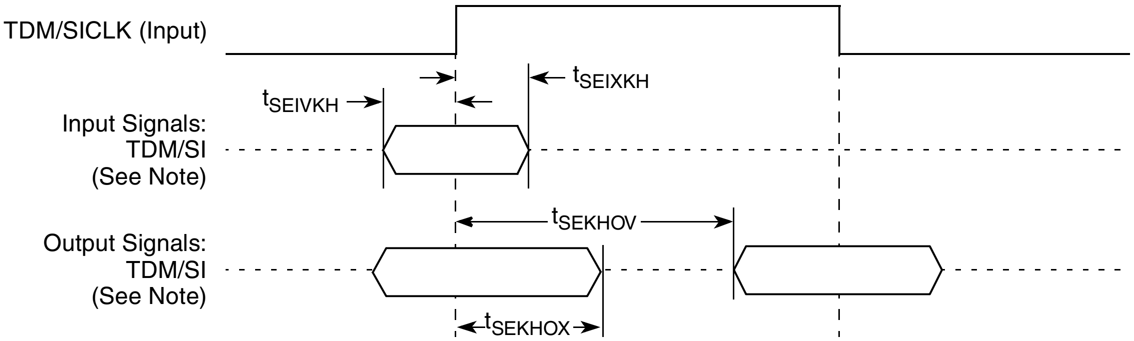


Figure 33. TDM/SI AC Test Load

Figure 34 represents the AC timing from Table 47. Note that although the specifications generally reference the rising edge of the clock, these AC timing diagrams also apply when the falling edge is the active edge.



Note: The clock edge is selectable on TDM/SI.

Figure 34. TDM/SI AC Timing (External Clock) Diagram

21 Package and Pin Listings

This section details package parameters, pin assignments, and dimensions. The MPC8323E is available in a thermally enhanced Plastic Ball Grid Array (PBGA); see Section 21.1, "Package Parameters for the MPC8323E PBGA," and Section 21.2, "Mechanical Dimensions of the MPC8323E PBGA," for information on the PBGA.

21.1 Package Parameters for the MPC8323E PBGA

The package parameters are as provided in the following list. The package type is 27 mm × 27 mm, 516 PBGA.

Package outline	27 mm × 27 mm
Interconnects	516
Pitch	1.00 mm
Module height (typical)	2.25 mm
Solder Balls	62 Sn/36 Pb/2 Ag (ZQ package) 95.5 Sn/0.5 Cu/4Ag (VR package)
Ball diameter (typical)	0.6 mm

21.2 Mechanical Dimensions of the MPC8323E PBGA

Figure 42 shows the mechanical dimensions and bottom surface nomenclature of the MPC8323E, 516-PBGA package.

Table 55. MPC8323E PBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
Power and Ground Supplies				
AV$_{DD}$1	P3	I	AV$_{DD}$1	—
AV$_{DD}$2	AA1	I	AV$_{DD}$2	—
AV$_{DD}$3	AB15	I	AV$_{DD}$3	—
AV$_{DD}$4	C24	I	AV$_{DD}$4	—
MVREF1	AB8	I	DDR reference voltage	—
MVREF2	AB17	I	DDR reference voltage	—
PCI				
PCI_INTA /IRQ_OUT	AF2	O	OV$_{DD}$	2
PCI_RESET_OUT	AE2	O	OV$_{DD}$	—
PCI_AD0/MSRCID0 (DDR ID)	L1	IO	OV$_{DD}$	—
PCI_AD1/MSRCID1 (DDR ID)	L2	IO	OV$_{DD}$	—
PCI_AD2/MSRCID2 (DDR ID)	M1	IO	OV$_{DD}$	—
PCI_AD3/MSRCID3 (DDR ID)	M2	IO	OV$_{DD}$	—
PCI_AD4/MSRCID4 (DDR ID)	L3	IO	OV$_{DD}$	—
PCI_AD5/MDVAL (DDR ID)	N1	IO	OV$_{DD}$	—
PCI_AD6	N2	IO	OV$_{DD}$	—
PCI_AD7	M3	IO	OV$_{DD}$	—
PCI_AD8	P1	IO	OV$_{DD}$	—
PCI_AD9	R1	IO	OV$_{DD}$	—
PCI_AD10	N3	IO	OV$_{DD}$	—
PCI_AD11	N4	IO	OV$_{DD}$	—
PCI_AD12	T1	IO	OV$_{DD}$	—
PCI_AD13	R2	IO	OV$_{DD}$	—
PCI_AD14/ECID_TMODE_IN	T2	IO	OV$_{DD}$	—
PCI_AD15	U1	IO	OV$_{DD}$	—
PCI_AD16	Y2	IO	OV$_{DD}$	—
PCI_AD17	Y1	IO	OV$_{DD}$	—
PCI_AD18	AA2	IO	OV$_{DD}$	—
PCI_AD19	AB1	IO	OV$_{DD}$	—

Table 55. MPC8323E PBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
PCI_AD20	AB2	IO	OV_{DD}	—
PCI_AD21	Y4	IO	OV_{DD}	—
PCI_AD22	AC1	IO	OV_{DD}	—
PCI_AD23	AA3	IO	OV_{DD}	—
PCI_AD24	AA4	IO	OV_{DD}	—
PCI_AD25	AD1	IO	OV_{DD}	—
PCI_AD26	AD2	IO	OV_{DD}	—
PCI_AD27	AB3	IO	OV_{DD}	—
PCI_AD28	AB4	IO	OV_{DD}	—
PCI_AD29	AE1	IO	OV_{DD}	—
PCI_AD30	AC3	IO	OV_{DD}	—
PCI_AD31	AC4	IO	OV_{DD}	—
PCI_C_$\overline{\text{BE0}}$	M4	IO	OV_{DD}	—
PCI_C_$\overline{\text{BE1}}$	T4	IO	OV_{DD}	—
PCI_C_$\overline{\text{BE2}}$	Y3	IO	OV_{DD}	—
PCI_C_$\overline{\text{BE3}}$	AC2	IO	OV_{DD}	—
PCI_PAR	U3	IO	OV_{DD}	—
$\overline{\text{PCI\_FRAME}}$	W1	IO	OV_{DD}	5
$\overline{\text{PCI\_TRDY}}$	W4	IO	OV_{DD}	5
$\overline{\text{PCI\_IRDY}}$	W2	IO	OV_{DD}	5
$\overline{\text{PCI\_STOP}}$	V4	IO	OV_{DD}	5
$\overline{\text{PCI\_DEVSEL}}$	W3	IO	OV_{DD}	5
PCI_IDSEL	P2	I	OV_{DD}	—
$\overline{\text{PCI\_SERR}}$	U4	IO	OV_{DD}	5
$\overline{\text{PCI\_PERR}}$	V3	IO	OV_{DD}	5
$\overline{\text{PCI\_REQ0}}$	AD4	IO	OV_{DD}	—
$\overline{\text{PCI\_REQ1}}$/CPCI_HS_ES	AE3	I	OV_{DD}	—
$\overline{\text{PCI\_REQ2}}$	AF3	I	OV_{DD}	—
$\overline{\text{PCI\_GNT0}}$	AD3	IO	OV_{DD}	—
$\overline{\text{PCI\_GNT1}}$/CPCI_HS_LED	AE4	O	OV_{DD}	—
$\overline{\text{PCI\_GNT2}}$/CPCI_HS_ENUM	AF4	O	OV_{DD}	—
M66EN	L4	I	OV_{DD}	—

Table 55. MPC8323E PBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
GPIO_PA26/Enet2_RX_ER/SER2_CD/TDMB_REQ/ LA10 (LBIU)	E26	IO	OV_{DD}	—
GPIO_PA27/Enet2_TX_ER/TDMB_CLKO/LA11 (LBIU)	F25	IO	OV_{DD}	—
GPIO_PA28/Enet2_RX_DV/SER2_CTS/ TDMB_RSYNC/LA12 (LBIU)	E25	IO	OV_{DD}	—
GPIO_PA29/Enet2_COL/RXD[4]/SER2_RXD[4]/ TDMB_STROBE/LA13 (LBIU)	J25	IO	OV_{DD}	—
GPIO_PA30/Enet2_TX_EN/SER2_RTS/ TDMB_TSYNC/LA14 (LBIU)	F26	IO	OV_{DD}	—
GPIO_PA31/Enet2_CRS/SDET LA15 (LBIU)	J26	IO	OV_{DD}	—
GPIO_PB0/Enet3_TXD[0]/SER3_TXD[0]/ TDMC_TXD[0]	A13	IO	OV_{DD}	—
GPIO_PB1/Enet3_TXD[1]/SER3_TXD[1]/ TDMC_TXD[1]	B13	IO	OV_{DD}	—
GPIO_PB2/Enet3_TXD[2]/SER3_TXD[2]/ TDMC_TXD[2]	A14	IO	OV_{DD}	—
GPIO_PB3/Enet3_TXD[3]/SER3_TXD[3]/ TDMC_TXD[3]	B14	IO	OV_{DD}	—
GPIO_PB4/Enet3_RXD[0]/SER3_RXD[0]/ TDMC_RXD[0]	B8	IO	OV_{DD}	—
GPIO_PB5/Enet3_RXD[1]/SER3_RXD[1]/ TDMC_RXD[1]	A8	IO	OV_{DD}	—
GPIO_PB6/Enet3_RXD[2]/SER3_RXD[2]/ TDMC_RXD[2]	A9	IO	OV_{DD}	—
GPIO_PB7/Enet3_RXD[3]/SER3_RXD[3]/ TDMC_RXD[3]	B9	IO	OV_{DD}	—
GPIO_PB8/Enet3_RX_ER/SER3_CD/TDMC_REQ	A11	IO	OV_{DD}	—
GPIO_PB9/Enet3_TX_ER/TDMC_CLKO	B11	IO	OV_{DD}	—
GPIO_PB10/Enet3_RX_DV/SER3_CTS/ TDMC_RSYNC	A10	IO	OV_{DD}	—
GPIO_PB11/Enet3_COL/RXD[4]/SER3_RXD[4]/ TDMC_STROBE	A15	IO	OV_{DD}	—
GPIO_PB12/Enet3_TX_EN/SER3_RTS/ TDMC_TSYNC	B12	IO	OV_{DD}	—
GPIO_PB13/Enet3_CRS/SDET	B15	IO	OV_{DD}	—
GPIO_PB14/CLK12	D9	IO	OV_{DD}	—
GPIO_PB15 UPC1_TxADDR[4]	D14	IO	OV_{DD}	—
GPIO_PB16 UPC1_RxADDR[4]	B16	IO	OV_{DD}	—

22.1 Clocking in PCI Host Mode

When the MPC8323E is configured as a PCI host device (RCWH[PCIHOST] = 1), CLKIN is its primary input clock. CLKIN feeds the PCI clock divider (÷2) and the PCI_SYNC_OUT and PCI_CLK_OUT multiplexors. The CFG_CLKIN_DIV configuration input selects whether CLKIN or CLKIN/2 is driven out on the PCI_SYNC_OUT signal.

PCI_SYNC_OUT is connected externally to PCI_SYNC_IN to allow the internal clock subsystem to synchronize to the system PCI clocks. PCI_SYNC_OUT must be connected properly to PCI_SYNC_IN, with equal delay to all PCI agent devices in the system.

22.1.1 PCI Clock Outputs (PCI_CLK_OUT[0:2])

When the MPC8323E is configured as a PCI host, it provides three separate clock output signals, PCI_CLK_OUT[0:2], for external PCI agents.

When the device comes out of reset, the PCI clock outputs are disabled and are actively driven to a steady low state. Each of the individual clock outputs can be enabled (enable toggling of the clock) by setting its corresponding OCCR[PCICOE*n*] bit. All output clocks are phase-aligned to each other.

22.2 Clocking in PCI Agent Mode

When the MPC8323E is configured as a PCI agent device, PCI_CLK is the primary input clock. In agent mode, the CLKIN signal should be tied to GND, and the clock output signals, PCI_CLK_OUT*n* and PCI_SYNC_OUT, are not used.

22.3 System Clock Domains

As shown in Figure 43, the primary clock input (frequency) is multiplied up by the system phase-locked loop (PLL) and the clock unit to create three major clock domains:

- The coherent system bus clock (*csb_clk*)
- The QUICC Engine clock (*ce_clk*)
- The internal clock for the DDR controller (*ddr_clk*)
- The internal clock for the local bus controller (*lb_clk*)

The *csb_clk* frequency is derived from a complex set of factors that can be simplified into the following equation:

$$csb\_clk = [\mathrm{PCI\_SYNC\_IN} \times (1 + {\sim}\overline{\mathrm{CFG\_CLKIN\_DIV}})] \times \mathrm{SPMF}$$

In PCI host mode, $\mathrm{PCI\_SYNC\_IN} \times (1 + {\sim}\overline{\mathrm{CFG\_CLKIN\_DIV}})$ is the CLKIN frequency.

The *csb_clk* serves as the clock input to the e300c2 core. A second PLL inside the core multiplies up the *csb_clk* frequency to create the internal clock for the core (*core_clk*). The system and core PLL multipliers are selected by the SPMF and COREPLL fields in the reset configuration word low (RCWL) which is loaded at power-on reset or by one of the hard-coded reset options. See the “Reset Configuration” section in the *MPC8323E PowerQUICC II Pro Communications Processor Reference Manual* for more information.

22.6 QUICC Engine PLL Configuration

The QUICC Engine PLL is controlled by the RCWL[CEPMF] and RCWL[CEPDF] parameters. Table 61 shows the multiplication factor encodings for the QUICC Engine PLL.

Table 61. QUICC Engine PLL Multiplication Factors

RCWL[CEPMF]	RCWL[CEPDF]	QUICC Engine PLL Multiplication Factor = RCWL[CEPMF]/ (1 + RCWL[CEPDF)
00000–00001	0	Reserved
00010	0	× 2
00011	0	× 3
00100	0	× 4
00101	0	× 5
00110	0	× 6
00111	0	× 7
01000	0	× 8
01001–11111	0	Reserved

The RCWL[CEVCOD] denotes the QUICC Engine PLL VCO internal frequency as shown in Table 62.

Table 62. QUICC Engine PLL VCO Divider

RCWL[CEVCOD]	VCO Divider
00	4
01	8
10	2
11	Reserved

NOTE

The VCO divider (RCWL[CEVCOD]) must be set properly so that the QUICC Engine VCO frequency is in the range of 300–600 MHz. The QUICC Engine frequency is not restricted by the CSB and core frequencies. The CSB, core, and QUICC Engine frequencies should be selected according to the performance requirements.

The QUICC Engine VCO frequency is derived from the following equations:

$$ce\_clk = (\text{primary clock input} \times \text{CEPMF}) \div (1 + \text{CEPDF})$$

$$\text{QUICC Engine VCO Frequency} = ce\_clk \times \text{VCO divider} \times (1 + \text{CEPDF})$$

Table 64. Package Thermal Characteristics for PBGA (continued)

Characteristic	Board type	Symbol	Value	Unit	Notes
Junction-to-package top	Natural convection	Ψ_{JT}	2	°C/W	6

Notes:

1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
2. Per JEDEC JESD51-2 with the single layer board horizontal. Board meets JESD51-9 specification.
3. Per JEDEC JESD51-6 with the board horizontal.
4. Thermal resistance between the die and the printed-circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
5. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).
6. Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written as Psi-JT.

23.2 Thermal Management Information

For the following sections, $P_D = (V_{DD} \times I_{DD}) + P_{I/O}$, where $P_{I/O}$ is the power dissipation of the I/O drivers.

23.2.1 Estimation of Junction Temperature with Junction-to-Ambient Thermal Resistance

An estimation of the chip junction temperature, T_J, can be obtained from the equation:

$$T_J = T_A + (R_{\theta JA} \times P_D)$$

where:

T_J = junction temperature (°C)

T_A = ambient temperature for the package (°C)

$R_{\theta JA}$ = junction-to-ambient thermal resistance (°C/W)

P_D = power dissipation in the package (W)

The junction-to-ambient thermal resistance is an industry standard value that provides a quick and easy estimation of thermal performance. As a general statement, the value obtained on a single layer board is appropriate for a tightly packed printed-circuit board. The value obtained on the board with the internal planes is usually appropriate if the board has low power dissipation and the components are well separated. Test cases have demonstrated that errors of a factor of two (in the quantity $T_J - T_A$) are possible.

23.2.2 Estimation of Junction Temperature with Junction-to-Board Thermal Resistance

The thermal performance of a device cannot be adequately predicted from the junction-to-ambient thermal resistance. The thermal performance of any component is strongly dependent on the power dissipation of surrounding components. In addition, the ambient temperature varies widely within the application. For many natural convection and especially closed box applications, the board temperature at the perimeter (edge) of the package is approximately the same as the local air temperature near the device. Specifying the local ambient conditions explicitly as the board temperature provides a more precise description of the local ambient conditions that determine the temperature of the device.

At a known board temperature, the junction temperature is estimated using the following equation:

$$T_J = T_B + (R_{\theta JB} \times P_D)$$

where:

T_J = junction temperature (°C)

T_B = board temperature at the package perimeter (°C)

$R_{\theta JB}$ = junction-to-board thermal resistance (°C/W) per JESD51-8

P_D = power dissipation in package (W)

When the heat loss from the package case to the air can be ignored, acceptable predictions of junction temperature can be made. The application board should be similar to the thermal test condition: the component is soldered to a board with internal planes.

23.2.3 Experimental Determination of Junction Temperature

To determine the junction temperature of the device in the application after prototypes are available, the thermal characterization parameter (Ψ_{JT}) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} \times P_D)$$

where:

T_J = junction temperature (°C)

T_T = thermocouple temperature on top of package (°C)

Ψ_{JT} = thermal characterization parameter (°C/W)

P_D = power dissipation in package (W)

The thermal characterization parameter is measured per JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over about 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

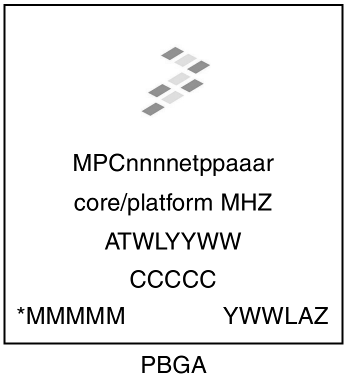
23.2.4 Heat Sinks and Junction-to-Case Thermal Resistance

In some application environments, a heat sink is required to provide the necessary thermal management of the device. When a heat sink is used, the thermal resistance is expressed as the sum of a junction-to-case thermal resistance and a case to ambient thermal resistance:

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CA}$$

25.2 Part Marking

Parts are marked as in the example shown in Figure 46.



Notes:
ATWLYYWW is the traceability code.
CCCCC is the country code.
MMMMM is the mask number.
YWWLAZ is the assembly traceability code.

Figure 46. Freescale Part Marking for PBGA Devices

26 Document Revision History

Table 67 provides a revision history for this hardware specification.

Table 67. Document Revision History

Rev. No.	Date	Substantive Change(s)
4	09/2010	• Replaced all instances of "LCCR" with "LCRR" throughout. • Added footnotes 3 and 4 in Table 2, "Recommended Operating Conditions[3]." • Modified Section 8.1.1, "DC Electrical Characteristics." • Modified Table 23, "MII Transmit AC Timing Specifications." • Modified Table 24, "MII Receive AC Timing Specifications." • Added footnote 7 and 8, and modified some signal names in Table 55, "MPC8323E PBGA Pinout Listing."
3	12/2009	• Removed references for note 4 from Table 1. • Added Figure 2 in Section 2.1.2, "Power Supply Voltage Specification. • Added symbol T_A in Table 2. • Added footnote 2 in Table 2. • Added a note in Section 4, "Clock Input Timing for rise/fall time of QE input pins. • Modified CLKIN, PCI_CLK rise/fall time parameters in Table 8. Modified min value of t_{MCK} in Table 19. • Modified Figure 43. • Modified formula for ce_clk calculation in Section 22.3, "System Clock Domains. • Added a note in Section 22.4, "System PLL Configuration. • Removed the signal ECID_TMODE_IN from Table 55. • Removed all references of RST signals from Table 55.